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INFORMATION DISCLOSURE STATEMENT BY APPLICANT Date Submitted: August 22, 2006 <i>(use as many sheets as necessary)</i>		Application Number	10/585,576
		Filing Date	12/28/2004
		First Named Inventor	Kazuya UEJIMA 4136
		Group Art Unit	Unassigned
		Examiner Name	Unassigned Duy T Nguyen
Attorney Docket Number	065686-0163		
Sheet	1	of	1

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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/D.N./	B1	Applied Physics, Vol. 65, No. 11, pp. 1131-1134, 1996.	
/D.N./	B2	M. TAMURA et al., "Secondary Defects in 1-10 keV As- and BF2-implanted Si," International Conference on Ion Implantation Technology Proceedings, pp. 744-747, 1999.	

Examiner Signature	/Duy Nguyen/	Date Considered	10/29/2008
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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